

10/506718

## UNITED STATES RECEIVING OFFICE (RO/US)

Re	International Appln. No. PCT/NL03/00171
International Filing Date	07 March 2003 (07.03.2003)
Applicant	RADDER, Arjen, Martijn et al.
Title of Invention	METHOD FOR MEASURING PARAMETERS AND A STRIKING DEVICE
Agent's File	R76.12-0001

## INFORMATION DISCLOSURE STATEMENT

Mail Stop PCT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

The patents or publications listed on the enclosed PTO Form-1449 are submitted pursuant to 37 C.F.R. § 1.97. Copies of the patents or publications cited are enclosed.

Submitted herewith is a copy (with English translation as appropriate) of an Official Search Report of the European Patent Office in counterpart foreign application No. PCT/NL03/00171 filed 07 March 2003.

Respectfully submitted,

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FORM PTO-1449	Atty. Docket No.: <b>10/506718</b>	App. No.:
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	First Named Inventor:	
	Filing Date	Group Art:

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
AA	4,991,850	2/1991	Wilhlem			
AB	5,351,952	10/1994	Hackman			
AC	5,816,580	10/1998	Gardner et al.			
AD	6,134,965	10/2000	Somville			
AE						
AF						
AG						
AH						
AI						
AJ						
AK						

FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Class	Sub Class	Translation Yes No
AL	1 011 942	3/2000	Belgium			X
AM	01 274783	11/1989	EPO (Japan Abstract)			X (abstract only)
AN	DE 3436218	4/1985	Germany			X-Abstract
AO	EP 0407631	1/1991	EPO			X-Abstract

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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